

40
CLAIMS

1. A semiconductor producing/examining device comprising:

5 a ceramic substrate having a conductor layer formed on the surface thereof or inside thereof; and a supporting case; in which an external terminal is connected to said conductor layer,

 wherein a connection between said conductor layer and said
10 external terminal is performed such that:

 said external terminal is pressed on said conductor layer;
or

 said external terminal is pressed on another conductor layer connected to said conductor layer.

15

2. The semiconductor-producing/examining device according to claim 1,

 wherein

 the connection between said conductor layer and said
20 external terminal, or

 the connection between said another conductor layer and said external terminal

 is performed by using elasticity of an elastic body.

25

3. The semiconductor-producing/examining device according to claim 1 or 2,

 wherein

 the connection between said conductor layer and said external terminal, or

30

 the connection between said another conductor layer and said external terminal

 is performed through a non-oxidizable metal layer.

4. The semiconductor-producing/examining device
35 according to any of claims 1 to 3,

